Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002
CB Certificate No.: DEKRA-T5A-003

Schedule Number: IECQ-L DEKRA 16.0002-S **Rev No.:** 6 **Revision Date:** 2025/07/20 **Page** 1 **of** 2

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202
High Humidity High Temp. Reverse Bias (H3TRB)	JESD22-A101, AEC-Q101
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operation test (LTOL)	JESD22-A108
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Acclerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Electrically Erasable Programmable ROM (EEPROM) Program/Erase Endurance and Data Retention Stress Test (Endurance and Data Retention)	JESD22-A117, AEC-Q100,
Power Cycling	JESD22-A122
NVM Endurance, Data Retention, and Operation Life (EDR)	AEC-Q100
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100
Steady-Status operation life	MIL-STD-750, MIL-STD-883
SAT	J-STD-020
2D X-ray	IPC-A-610
3D X-ray	A00-340-30071
3D OM	A00-340-30066
Reflow test	J-STD-020

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Solderability test		J-STD-020, JESD22-B102
Chemical Analysis		IEC62321, EN14582, IPC-TM-650
X-section/ SEM		IPC-TM-650, IPC-A-610, JESD22-A121A
OBIRCH		A00-510-30003
InGaAs		A00-510-30028
Thermal EMMI		A00-510-30038
Surge		A00-510-30043
TLP		A00-510-30010
I-V measurement		A00-510-30029
Sample Preparation (Decap)		A00-520-30041
2nd level integration platform service (Military)	Pre-SMT	J-STD-020, JESD22-A113
	SMT	IPC-7525, IPC-A-610, JESD22-A111, J-STD-002, J-STD-003, MIL-STD-202
	Temperature Cycling test	IPC-9701, JESD22-A104, JESD22-A106 EIAJ ED-4702, AEC-Q007, AEC-Q104 IEC-60068-2-14, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Temperature-Humidity test	JESD22-A101, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Drop/Shock	JESD22-B110, JESD22-B111, AEC-Q104 MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883
	Vibration	JESD22-B103, AEC-Q104, MIL-STD-202 MIL-STD-750, MIL-STD-810, MIL-STD-883
	Hermeticity	JESD22-A109
	Package Warpage Measurement of Surface-Mount Integrated Circuits at Elevated Temperature	JESD22-B108, JESD22-B112, JESD22-B110
	Printed Wiring Board Strain Gage Test	IPC-9703

DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands